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The low thermal gradient Czochralski crystal growth and microstructural properties of a Pb₂MoO₅(20-1) cleaved surface

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Abstract

The optical quality Pb₂MoO₅ single crystals were grown by the Low Thermal Gradient Czochralski Technique (LTG Cz). As a result, the Pb₂MoO₅ crystals with the diameter of 40-50 mm and the length of ~100 mm were grown. The grown crystals phase composition was identified by the X-ray single crystal structure analysis in space group C2/m, a = 14.2221(11), b = 5.7852(5), c = 7.3262(6) Å, $\beta = 114.168(2)^\circ$, Z = 4 ($R_1 = 0.0336$). The Pb₂MoO₅(20-1) substrates were prepared by cleavage, and the surface properties were evaluated by RHEED and AFM. The superposition of wide Kikuchi lines and crystal reflexes was found by RHEED. The AFM measurements indicate as low surface roughness as ~0.2 nm. Thus, the atom smooth surface of Pb₂MoO₅ was formed by cleavage.

Keywords: Pb₂MoO₅, cleavage, microstructure, RHEED, AFM

1. Introduction

Crystals with a layered structure comprise relatively weak chemical bonds in a selected direction, and this results in strong anisotropy of their basic chemical and physical properties, including chemical reactivity, mechanical, thermal, electronic and optical parameters [1-6]. Layered crystals may possess good cleavage properties along the specific crystallographic direction with the formation of a large area cleaved surface showing an excellent structural quality up to the nanometric level. In layered chalcogenides, where metal-chalcogen bonds are long and interlayer links are formed by weak van der Waals bonds, the preparation of an atomic smooth substrate surface by cleavage is widely used in experimental techniques [3,7-9]. As for oxide crystals, the detail studies of man-made crystal cleaved surface, to our best knowledge, are very scarce in the literature and dominantly belong to wolframite-family tungstates. Now, it is clear that bulk crystal quality is a key factor to get the atomic-smooth cleaved surface. In the past, from empirical experience, several other oxide crystals with cleavage properties were discovered, and, commonly, this feature was considered negative in optical and electronic applications because serious problems may appear during a sample's cutting and polishing.

Double lead molybdate Pb_2MoO_5 , space group C2/m, belongs to the family of Pb_2XO_5 (X = S, Cr, Mo, W) compounds with a framework type structure [10,11]. The Pb_2MoO_5 crystal structure is shown in Fig. 1 [11,12]. The structure is formed by corner linked PbO₉ polyhedrons and distorted MoO₄ tetrahedra and can be classified as a framework without evident layer formation. However, the Pb-O bond lengths in the PbO₉ polyhedrons are strongly different and, if to remove the comparatively long bonds Pb1-O2, Pb1-O3, Pb2-O2 and Pb2-O1 in the range of 261.5-381.3 pm [10], as shown in Fig. 1, the layered structure can be found. The complex layers are parallel to (20-1) planes.

Presently, Pb₂MoO₅ is considered as one of the best known acousto-optical (AO) materials because of its high AO figure of merit [13-16]. Pb₂MoO₅ melts congruently and, respectively, large perfect single crystals can be grown by efficient Czochralski method [17-19]. The mechanical



Fig. 1. A fragment of the Pb₂MoO₅ crystal structure. The unit cell is outlined. Lone atoms are omitted for clarity. Only comparatively short bonds Pb1-O4, Pb1-O1, Pb2-O4 and Pb2-O3 are shown.

properties of the Pb₂MoO₅ crystal permit the boule cutting and preparation of the sample in an arbitrary crystallographic direction needed for physical parameter measurements [13-17,20-23]. Nevertheless, the pronounced cleavage parallel to plane (20-1) was reported in the literature [14,16,20]. The cleavage effect is evidently provided by disruption of comparatively long Pb-O bonds between the layers shown in Fig. 1. The structural and chemical properties of the (20-1) cleaved surface in Pb₂MoO₅ remain to be unknown. Thus, the present study is aimed at the Pb₂MoO₅ crystal growth under the low thermal gradient conditions and evaluation of cleaved (20-1) surface microstructural properties.

2. Experimental

The Pb₂MoO₅ single crystals were grown along the direction orthogonal to the cleavage plane. Initially, the oriented seed was prepared by cleavage of the mm-size Pb₂MoO₅ crystals grown by spontaneous crystallization from the stoichiometric melt. The diameter of the cleaved (20-1) seed face was ~10 mm. The seed was clamped onto the Pt rod, and the Pb₂MoO₅ single crystals were

grown by the Low Thermal Gradient Czochralski Technique (LTG Cz) [24-27]. The use of LTG Cz decreases the losses of volatile PbO and MoO₃ oxides because the significant melt overheating during growth is avoided. The initial charge was prepared using lead(II,IV) oxide Pb₃O₄ (reagent grade, Shymkent lead plant, Kazakhstan) and molybdenum oxide MoO₃. Previously, the MoO₃ oxide was deeply purified by double sublimation with subsequent double recrystallization in aqueous solutions. The purification technology is well developed in NIIC (Novosibirsk, Russia) [28]. The stoichiometric oxide mixture was inserted into a platinum crucible with the diameter of 70 mm and the height of 150 mm. Then, the charge was heated at the rate of 50 grad/h into the growth chamber up to 970–980 °C in the air. Before seeding, the melt was being homogenized during 12 h. The Pb₂MoO₅ crystals were grown at the rate of 0.3-2.5 mm/h and at the rotation rate of 12 rpm. The temperature gradient at the growth front was not above 0.1-0.2 grad/mm. As a result, the Pb₂MoO₅ crystals with the diameter of 40-50 mm and the length of ~70-100 mm were grown. The crystal weight was up to 800 g. The Pb₂MoO₅ crystal grown by the LTG Cz method is shown in Fig. 2.



Fig. 2. A Pb₂MoO₅ crystal grown by the LTG Cz technique. The seeding and bottom parts are cut.

The single-crystal X-ray diffraction experiment for compound Pb₂MoO₅ was carried out with a Bruker Nonius X8 Apex diffractometer equipped with a 4K CCD detector, using graphite monochromated MoK_{α} radiation ($\lambda = 0.71073$ Å) at ambient temperature. Reflection intensities were integrated using the SAINT software and corrected for absorption by the semi-empirical method (SADABS program) [29]. The structures were solved by the direct method with SIR2004 [30] and refined by the full-matrix least squares method against F^2 on all data using the SHELXTL software [31]. All the atoms were refined in the anisotropic approximation. The crystallographic parameters of the studied Pb₂MoO₅ crystal are given in Table 1, and the atom coordinates are given in Table 1S (in the supplement). The bond lengths and angles are given in Table 2S (in the supplement). The structural parameters of Pb₂MoO₅ defined in the present experiment are in good relation with those obtained by powder methods [11]. CSD 428844 contains supplementary crystallographic data for compound Pb₂MoO₅ in ICSD.

Empirical formula	MoO ₅ Pb ₂
Formula weight	590.32
Temperature	293(2) K
Wavelength	0.71073 Å
Crystal system	Monoclinic
Space group	<i>C</i> 2/ <i>m</i>
Unit cell dimensions	a = 14.2221(11) Å
	b = 5.7852(5) Å
	c = 7.3262(6) Å
	β=114.168(2)°
Volume	549.95(8) Å ³
Ζ	4
Density (calculated)	7.130 Mg/m ³
Absorption coefficient	63.251 mm ⁻¹
F(000)	984
Crystal size	0.06 x 0.05 x 0.02 mm

Table 1.	Crystal	l data and	structure	refinement	for F	⁰b₂Mc	٥O
						_	

Theta range for data collection	3.05 – 32.57°
Reflections collected	2753
Independent reflections	1089 ($R_{\rm int} = 0.0414$)
Completeness to theta = 25.00°	99.8 %
Data / restraints / parameters	1089 / 0 / 52
Goodness-of-fit on F^2	1.036
Final <i>R</i> indices ($I \ge 2\sigma_I$)	$R_1 = 0.0336, wR_2 = 0.0834$
<i>R</i> indices (all data)	$R_1 = 0.0358, wR_2 = 0.0851$
Largest diff. peak and hole	5.415 and -6.071 e/Å ³

The X-ray rocking curves were recorded using a two-crystal diffractometer DSO-1T ($Cu_{K\alpha 1}$ radiation, $\lambda = 1.54056$ Å) equipped with the Ge(004) monochromator. Initially, the substrate plane was adjusted to be parallel to the X-ray beam and, then, the angles of possible diffraction reflections were found by symmetrical scanning (ω -scan). In accordance with the calculations, the reflections of 1-4 orders from (20-1) planes should be at 7.31, 14.74, 22.43, 30.58° in reference to the surface normal. In the experiment with a cleaved Pb₂MoO₅ surface, all these reflections were observed at the calculated angles, and that verifies the cleaved plane orientation.

AFM patterns from the cleaved surfaces were recorded using Solver P47-PRO (NT-MDT, Russia) in the semicontact mode. The NSG 11 (NT-MDT, Russia) contilever was installed for the measurements. The top-surface crystallographic properties were evaluated with RHEED using an EFZ4 (Carl Zeiss, Germany) device at electron energy 50 keV.

3. Results and discussion

The grown Pb₂MoO₅ crystal with the diameter of 40-50 and the length of 70 mm is shown in Fig. 2. The crystal is partly faceted and transparent in the central crystal part. Over the peripheric boule parts, however, the scattering centers were detected under laser beam illumination ($\lambda = 0.6328 \mu$ m). The evidence of light-yellow coloration is not clear, and this effect can be supposedly attributed to an admixture of foreign metal ions from the lead oxide. As it is reasonably appeared,

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 MoO_3 can not be a source of coloration because other crystals grown using this starting reagent, for example ZnMoO₄, were transparent over visible spectral range [28]. The crystallization front structure is shown in Fig. 3. The central flat part of the crystal is evidently formed due to the layer-



Fig. 3. Bottom part of the Pb₂MoO₅ boule.

by-layer growth mechanism starting from the (20-1) seed surface. The area of this flat part is ~ 230 mm² onto the crystal bottom that is two times higher than the seed face area. The peripheric crystal part is formed by the macro- and micro-terraces, and they indicate that the block growth mechanism appeared over these regions. Generally, it can be concluded that the internal structure of the Pb₂MoO₅ boule is complex. During the LTG Cz growth, two growth mechanisms function in parallel, and the crystal diameter increases dominantly by block growth over the external crystal parts. The central corn crystal part also increases in diameter starting from the seed to the crystal bottom, but the variation is less significant.

To evaluate the internal crystal quality, the $Pb_2MoO_5(20-1)$ substrates with the diameter of ~24 mm and thicknesses in the range of 1.5-2.5 mm were prepared by cleaving the crystal with a steel

knife in the air. The bulk structural quality can be estimated by the rocking curve comparison, as shown in Fig. 4. The full width at a half maximum (FWHM) of the diffraction peak measured from



Fig. 4. Rocking curves recorded for reflex (40-2) from the (black) central and (red) peripheric parts of cleaved Pb₂MoO₅(20-1) substrate.

the central part of the substrate is ~ 30''. Comparatively, at the periphery of the substrate, the FWHM parameter is ~300'' high due to the blocked type structure. The RHEED pattern recorded from a cleaved crystal surface is shown in Fig. 5. The superposition of wide Kikuchi lines and crystal reflexes is evident, and that verifies an excellent surface structural quality. There is no amorphous component detected at the cleaved surface that is similar to the cleaved surface state previously observed in AWO₄ (A = Zn, Cd) tungstates [25-26].



Fig. 5. A Kikuchi lines pattern recorded by RHEED for the cleaved Pb₂MoO₅(20-1) surface. The electron beam is along [212].

The results of AFM measurements are shown in Figs. 6 and 7. A typical topographic AFM image and surface profile are shown in Fig. 6 (a) and (b), respectively. Commonly, the surface is formed by a system of wide plane regions with as low roughness as ~0.2 nm. As shown in Fig. 7, the elementary level step ~0.65 nm between the terraces is in reasonable relation with the *d*-spacing of 0.61 nm estimated by RHEED. Thus, the cleaved $Pb_2MoO_5(20-1)$ surface can be classified as the atomically smooth one. Besides, a very interesting example of occasional formations onto the surface is shown in Fig. 1S (in the supplement). One can see the strip-shape elementary layer terrace crossed by a low-level terrace boundary. The height of the low-level step is as low as ~0.1 nm, and, as it seems, this formation appeared due to an incomplete layer step. It is not clear, however, either this incomplete atom layer is on the elementary layer terrace surface or barred in the crystal bulk. This AFM pattern may indicate the possibility of the presence of an incomplete layer defect in the Pb₂MoO₅ crystal bulk.



Fig. 6. An AFM pattern recorded from the Pb₂MoO₅(20-1) cleaved surface: (a) panoramic view and(b) depth profile.



Fig. 7. An AFM pattern recorded from the region of the Pb₂MoO₅(20-1) cleaved surface with the elementary step: (a) panoramic view and (b) depth profile.

4. Conclusions

As it is shown in the present study, the atomic smooth crystal surface of Pb_2MoO_5 can be prepared by cleavage. The structural quality of the Pb_2MoO_5 crystals grown by LTG Cz is good enough for the preparation of large area substrate suitable for physical parameter measurements. As it was found in the present study, the bulk structure of the Pb_2MoO_5 boule is complex. The central part is formed by a tapered corn with the diameter increasing from seed to bottom. The corn is surrounded by the blocked crystal material with a lower structural quality. Further LTG Cz growth technology optimization is evidently topical to increase the corn diameter more. Due to structural similarity, good cleavage properties can also be supposed for other crystals related to the Pb_2XO_5 (X = S, Cr, Mo, W) family.

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The high-quality Pb₂MoO₅ crystal has been grown by LTG Cz method.